

FQP11N50CF / FQPF11N50CF N-Channel QFET® FRFET® MOSFET

500 V, 11 A, 550 mΩ

Description

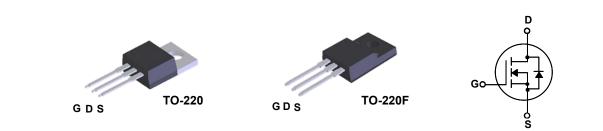
This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

• 11 A, 500 V, $R_{DS(on)}$ = 550 m $\Omega(Max.)$ @V_{GS} = 10 V, I_D = 5.5 A

March 2013

- Low Gate Charge (Typ. 43 nC)
- Low C_{rss} (Typ. 20 pF)
- 100% Avalanche Tested
- Fast Recovery Body Diode (Typ. 90 ns)



Absolute Maximum Ratings

| Symbol | Parameter | | FQP11N50CF | FQPF11N50CF | Unit |
|-----------------------------------|--|----------|-------------|-------------|------|
| V _{DSS} | Drain-Source Voltage | | 5 | 500 | |
| I _D | Drain Current - Continuous (T _C = 25°C | ;) | 11 | 11 * | А |
| | - Continuous (T _C = 100°C) | | 7 | 7 * | А |
| I _{DM} | Drain Current - Pulsed | (Note 1) | 44 | 44 * | А |
| V _{GSS} | Gate-Source Voltage | | ± 30 | | V |
| E _{AS} | Single Pulsed Avalanche Energy (Note | | 670 | | mJ |
| I _{AR} | Avalanche Current | (Note 1) | 11 | | А |
| E _{AR} | Repetitive Avalanche Energy (Note 1) | | 19.5 | | mJ |
| dv/dt | Peak Diode Recovery dv/dt (Note 3) | | 4.5 | | V/ns |
| P _D | Power Dissipation (T _C = 25°C) | | 195 | 48 | W |
| | - Derate above 25°C | | 1.56 | 0.39 | W/°C |
| T _J , T _{STG} | Operating and Storage Temperature Range | | -55 to +150 | | °C |
| Τ _L | Maximum lead temperature for soldering p 1/8" from case for 5 seconds | 300 | | °C | |

* Drain current limited by maximum junction temperature

Thermal Characteristics

| Symbol | Parameter | FQP11N50CF | FQPF11N50CF | Unit |
|-----------------|---|------------|-------------|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case | 0.64 | 2.58 | °C/W |
| $R_{\theta JS}$ | Thermal Resistance, Case-to-Sink Typ. | 0.5 | | °C/W |
| R_{\thetaJA} | Thermal Resistance, Junction-to-Ambient | 62.5 | 62.5 | °C/W |

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Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|-------------|---------|-----------|------------|----------|
| FQP11N50CF | FQP11N50CF | TO-220 | | | 50 |
| FQPF11N50CF | FQPF11N50CF | TO-220F | | | 50 |

Electrical Characteristics T_C = 25°C unless otherwise noted

| Symbol | Parameter | Test Conditions | Min. | Тур. | Max. | Unit |
|------------------------------|---|---|------|------|------|------|
| Off Charac | teristics | | | 1 | 1 | |
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} = 0 V, I _D = 250 μA | 500 | | | V |
| $\Delta BV_{DSS}/\Delta T_J$ | Breakdown Voltage Temperature Coefficient | I_D = 250 µA, Referenced to 25°C | | 0.5 | | V/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = 500 V, V _{GS} = 0 V | | | 10 | μA |
| | | V _{DS} = 400 V, T _C = 125°C | | | 100 | μA |
| I _{GSSF} | Gate-Body Leakage Current, Forward | V_{GS} = 30 V, V_{DS} = 0 V | | | 100 | nA |
| I _{GSSR} | Gate-Body Leakage Current, Reverse | V_{GS} = -30 V, V_{DS} = 0 V | | | -100 | nA |
| On Charact | eristics | | I. | | 1 | 4 |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$ | 2.0 | | 4.0 | V |
| R _{DS(on)} | Static Drain-Source On-Resistance | V _{GS} = 10 V, I _D = 5.5 A | | 0.48 | 0.55 | Ω |
| 9 _{FS} | Forward Transconductance | $V_{DS} = 40 \text{ V}, \text{ I}_{D} = 5.5 \text{ A}$ (Note 4) | | 15 | | S |
| Dynamic C | haracteristics | | I. | | 1 | 4 |
| C _{iss} | Input Capacitance | V_{DS} = 25 V, V_{GS} = 0 V, | | 1515 | 2055 | pF |
| C _{oss} | Output Capacitance | f = 1.0 MHz | | 185 | 235 | pF |
| C _{rss} | Reverse Transfer Capacitance | - | | 25 | 30 | pF |
| Switching | Characteristics | 1 | 1 | | 1 | 1 |
| t _{d(on)} | Turn-On Delay Time | V _{DD} = 250 V, I _D = 11 A, | | 24 | 57 | ns |
| t _r | Turn-On Rise Time | R _G = 25 Ω | | 70 | 150 | ns |
| t _{d(off)} | Turn-Off Delay Time | | | 120 | 250 | ns |
| t _f | Turn-Off Fall Time | (Note 4, 5) | | 75 | 160 | ns |
| Qg | Total Gate Charge | V _{DS} = 400 V, I _D = 11 A, | | 43 | 55 | nC |
| Q _{gs} | Gate-Source Charge | V _{GS} = 10 V | | 8 | | nC |
| Q _{gd} | Gate-Drain Charge | (Note 4, 5) | | 19 | | nC |
| • | ce Diode Characteristics and Maximum Rat | ings | | 1 | 1 | |
| I _S | S Maximum Continuous Drain-Source Diode Forward Current | | | | 11 | Α |
| I _{SM} | Maximum Pulsed Drain-Source Diode Forward Current | | | | 44 | Α |
| V _{SD} | Drain-Source Diode Forward Voltage | V _{GS} = 0 V, I _S = 11 A | | | 1.4 | V |
| t _{rr} | Reverse Recovery Time | V _{GS} = 0 V, I _S = 11 A, | | 90 | | ns |
| Q _{rr} | Reverse Recovery Charge | $dI_{F} / dt = 100 \text{ A}/\mu \text{s}$ (Note 4) | | 1.5 | | μC |

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature

2. L = 10 mH, I_{AS} = 11 A, V_{DD} = 50V, R_G = 25 $\Omega,$ Starting $\mbox{ T}_{J}$ = 25°C

3. I_{SD} \leq 11 A, di/dt \leq 200 A/µs, V_{DD} \leq BV_{DSS,} Starting ~T_J = 25°C

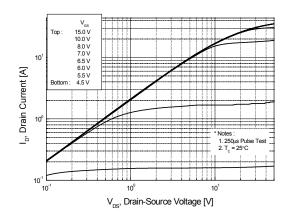
4. Pulse Test : Pulse width $\leq 300~\mu s,~\text{Duty cycle} \leq 2\%$

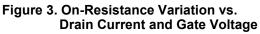
5. Essentially independent of operating temperature

Typical Performance Characteristics



Figure 2. Transfer Characteristics





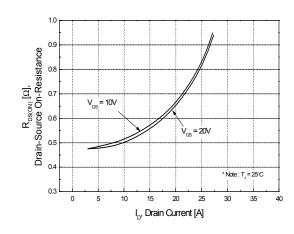
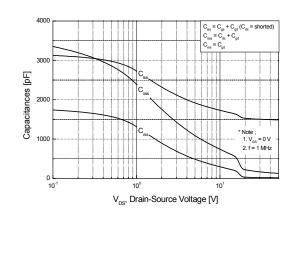


Figure 5. Capacitance Characteristics



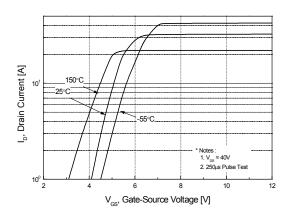


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

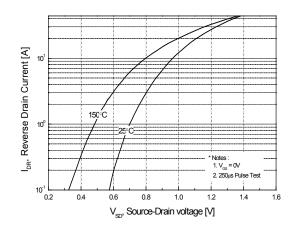
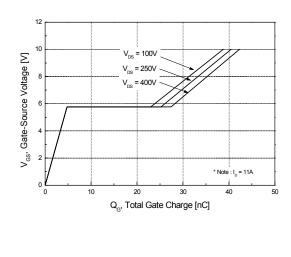
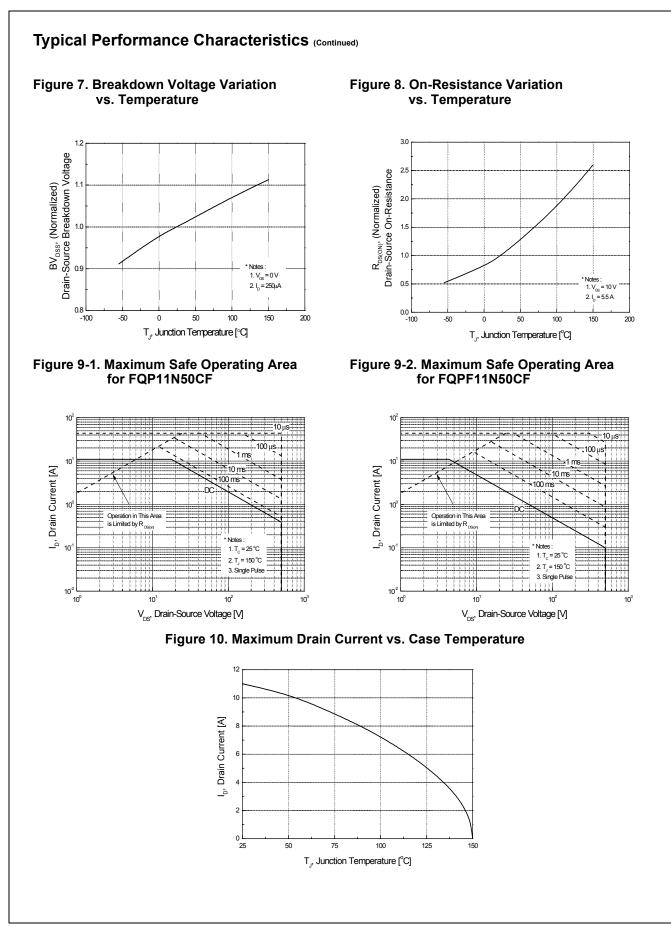


Figure 6. Gate Charge Characteristics





Typical Performance Characteristics (Continued)



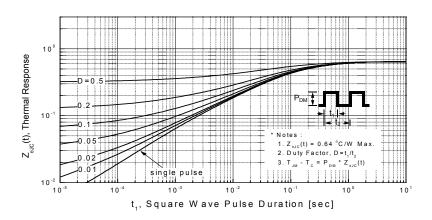
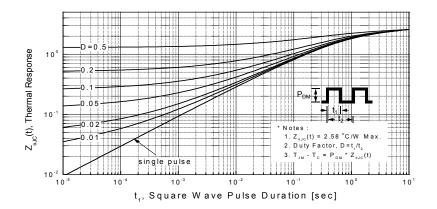
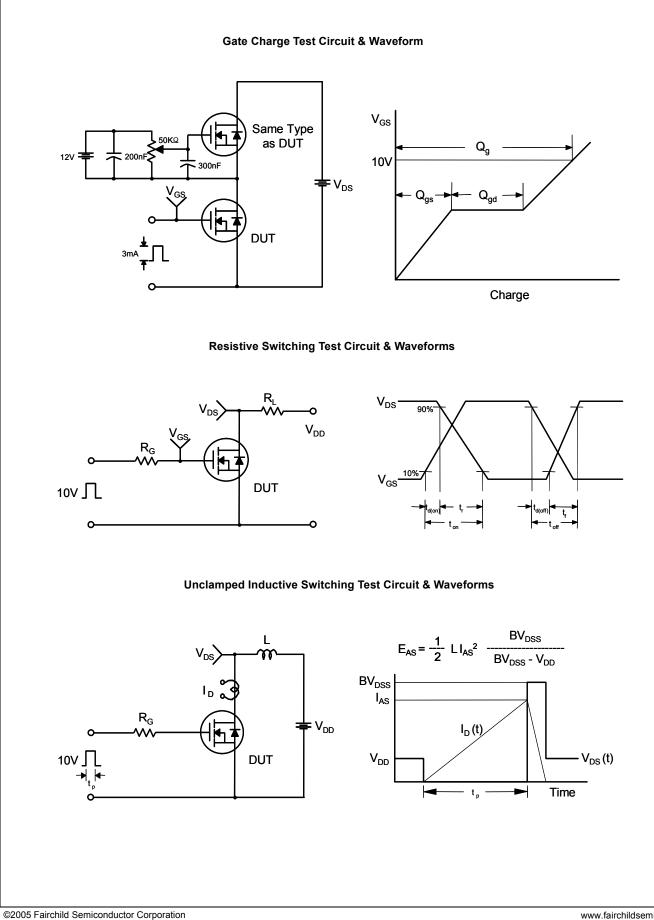


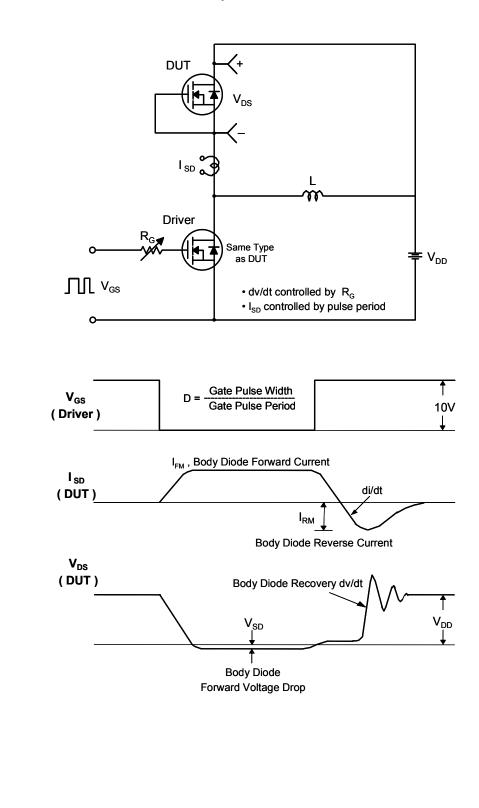
Figure 11-2. Transient Thermal Response Curve for FQPF11N50CF

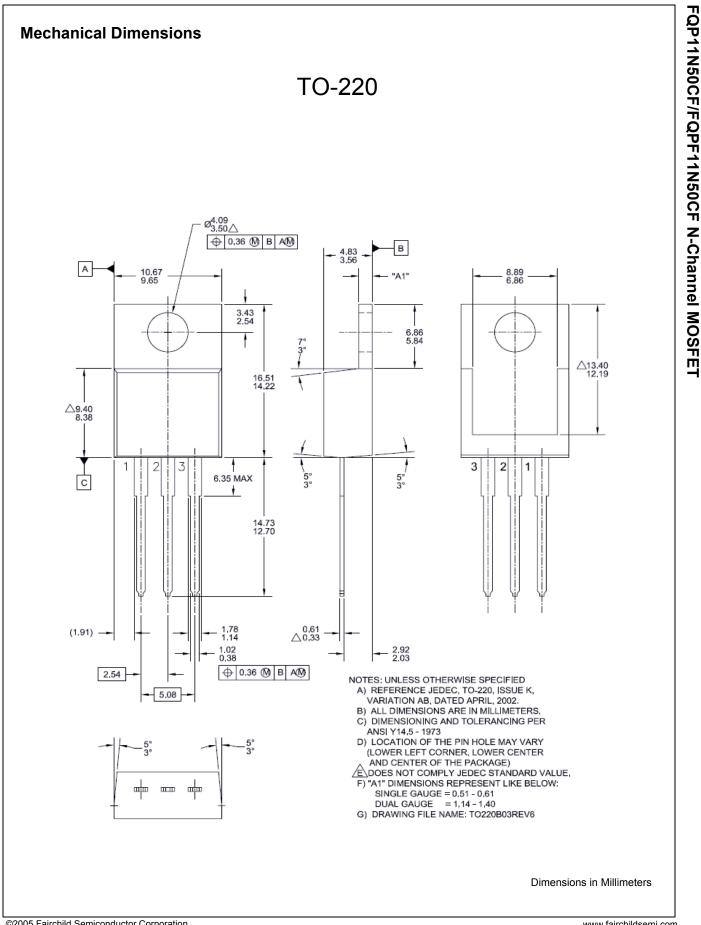


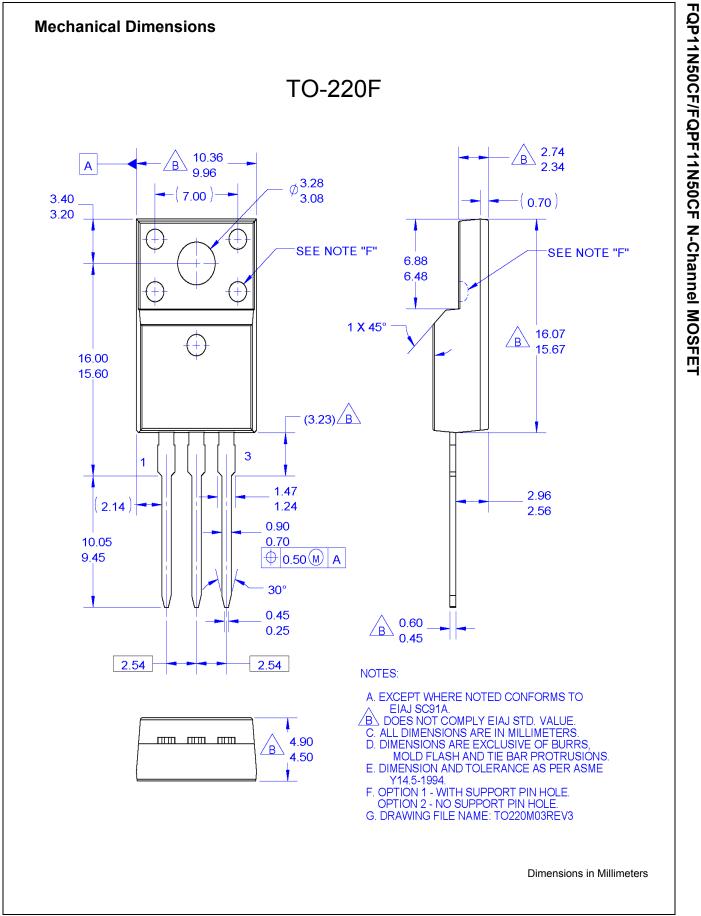


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Peak Diode Recovery dv/dt Test Circuit & Waveforms









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